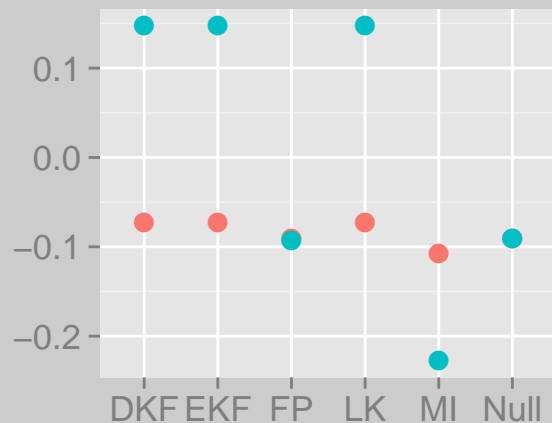


Bias

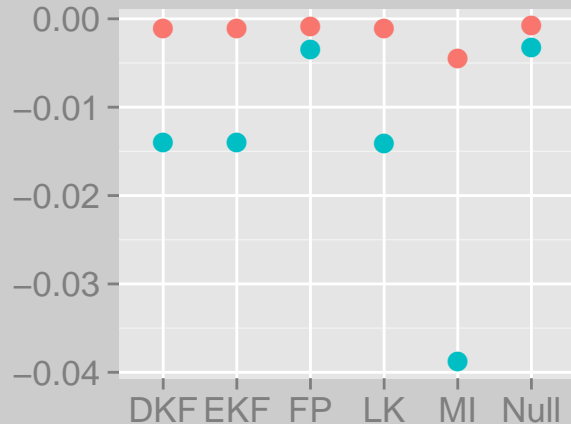
Measurement



Process Noise



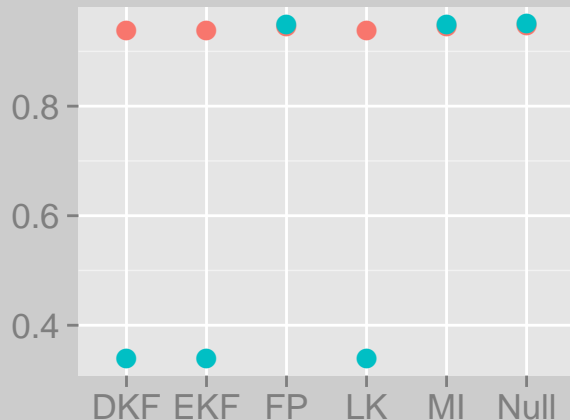
Time Series



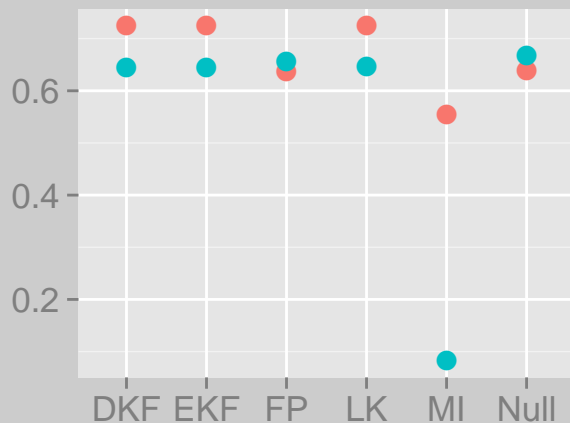
FittedIC

Coverage Rates

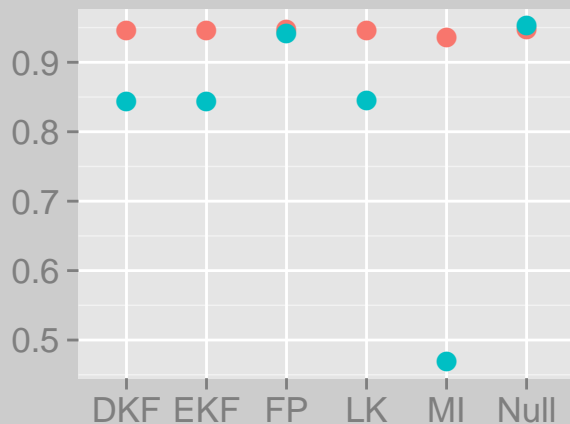
Measurement



Process Noise



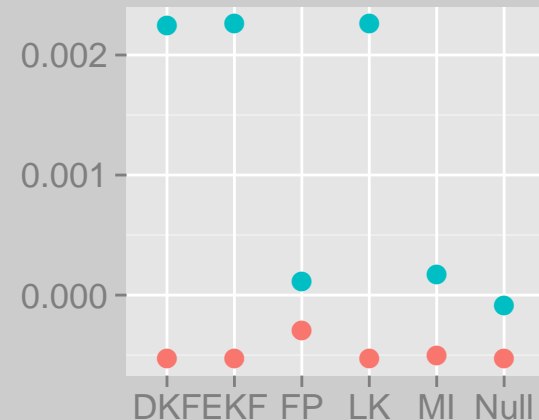
Time Series



FittedIC

SD - SE

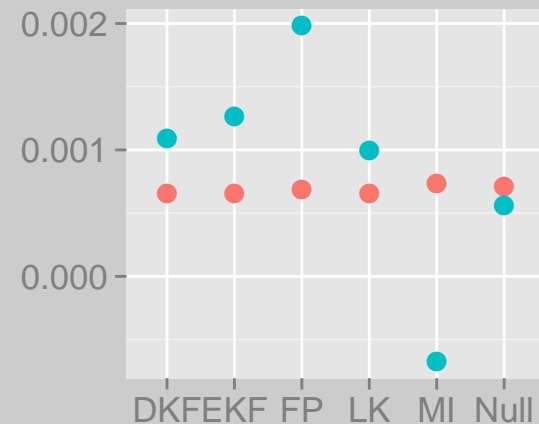
Measurement



Process Noise



Time Series



FittedIC